

METHOD AND APPARATUS FOR SELECTING
AN ENCRYPTION INTEGRATED CIRCUIT OPERATING MODE

ABSTRACT OF THE DISCLOSURE

A method and circuit for preventing external access to secure data of an
5 integrated circuit while supporting DFT is disclosed. In accordance with the method the
integrated circuit is automatically placed into the test mode at integrated circuit power-
up from a power-down state. At power up, secure data is other than present within a
secure data-path of the integrated circuit. Access is provided to the secure data path via
a second data path coupled with the first secure data-path. Via the access path, data
10 other than secure data is provided to the integrated circuit, the data for performing test
functions of the integrated circuit operating in the test mode. Once data other than
secure data is provided to first secure data path, the test mode is terminated and access
via other than the secure ports is disabled. The test mode is only re-entered by powering
down the integrated circuit and re-initialising it.